	26	arcn	Notes	
-				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/644,576	SANCHEZ ET AL.
Examiner	Art Unit
Yong S Chang	1617

SEARCHED				
Class	Subclass-	Date	Examiner	
514	469	6/15/2005	YSC	
558	422	6/15/2005	YSC	
	Search	2/2/06	YIL	
Updated Upo	Deach	A24/06	YSL	
Ира	ated	3/20/01	YSC	
			•	
		•		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
UI II	8 7				
ļ	<u></u>				

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
Inventor (EAST, PALM)	6/15/2005	YSC	
Text (EAST, STN)	6/15/2005	YSC	
Updated Search	2/2/06	Ysc	
Updated Search	8/28/00	4se	
Updated	3/201	YSZ	